

## **Biography**

Filippo Giannazzo (PhD) joined CNR-IMM as a researcher in 2006 and is senior researcher from 2010. He is expert in scanning probe microscopy methods for the characterization of carrier transport properties in advanced materials for micro- and nanoelectronics (wide-bandgap semiconductors, heterostructures, dielectrics, 2D materials). Author of more than 300 papers, 10 book chapters (H-index=38, 4500 citations, source Scopus) and an international patent, he is frequently invited speaker in national and international conferences. He holds several national and international collaborations with academic institutions and industries. Involved in several national and EU projects, he is currently coordinating the FlagERA JTC-2019 project ETMOS.